

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/614,217	CHA, ELLIS T.	
Examiner	Art Unit	
Tianjie Chen	2656	

	SEARCHED				
Class	Subclass	Date	Examiner		
Updated		5/2/2006	ΤJ		
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INT	INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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